

International Symposium on Reliability

The first symposium in Japan about reliability issues related to electronics such as soft errors, aging degradations to threaten our safety, which consists of the keynote and several invited talks by distinguished researchers from all over the world.

Monday, March 19th, 2018

60th Anniversary Hall, Kyoto Institute of Technology

► Program

- 13:00-13:20** **Opening & Introduction**
Prof. Kazutohi Kobayashi (Kyoto Institute of Technology, Japan)
- 13:20-14:40** **Keynote Speech**
The Interaction of Security and Reliability in the Deep-nanometer Age
Dr. Charles Slayman (Cisco Systems, Inc, USA)
Chair: Prof. Kazutohi Kobayashi (Kyoto Institute of Technology, Japan)
- 14:40-14:50** **Break**
Chair: Dr. Taiki Uemura (Samsung Electronics, Korea)
- Session 1**
14:50-15:30 **Invited Talk 1**
Silicon Odometers: Past, Present, and Future,
Prof. Chris Kim (University of Minnesota, USA)
- 15:30-16:10** **Invited Talk 2**
SRAM Soft Error Rate - Technology Trends and Measurement Techniques., Dr. Frank Schlaphof (GLOBALFOUNDRIES, Germany)
- 16:00-16:20** **Break**
Chair: Prof. Shigetaka Kumashiro (Kyoto Institute of Technology, Japan)
- Session 2**
16:20-17:00 **Invited Talk 3**
Improving Energy Efficiency and Resilience of Electronic Products by Static and Dynamic Compensation Schemes
Dr. Souhir Mhira in the proxy of Dr. Vincent Huard (STMicroelectronics, France)
- 17:00-17:40** **Invited Talk 4**
Reliability Issues and radiation effects on emerging non-volatile memories, Prof. Jinshun Bi (Institute of Microelectronics of Chinese Academy of Science, China)
- 17:40-17:50** **Closing**
Prof. Kazutohi Kobayashi (Kyoto Institute of Technology, Japan)
- 18:00-20:00** **Reception**

► Keynote and Invited Speakers



Dr. Charles Slayman

Cisco Systems, Inc, USA



Dr. Souhir Mhira

STMicroelectronics, France



Dr. Frank Schlaphof

GLOBALFOUNDRIES, Germany



Prof. Chris Kim

University of Minnesota, USA



Prof. Jinshun Bi

Institute of Microelectronics of Chinese Academy of Science, China

Registration fee : FREE

Sponsor
Cooperation

Green Innovation Center, Kyoto Institute of Technology
Consortium for "Quantum Innovation for Safe, Secure, Smart Society (QISS)" supported by JST OPERA
IEEE SSCS Kansai Chapter
IEEE SSCS Japan Chapter

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